



22nd IEEE European Test Symposium

Amathus Beach Hotel
Limassol, Cyprus | May 22 – 26, 2017
www.ets17.org.cy



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Final Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuits and system testing and reliability. In 2017, ETS will take place at Amathus Beach Hotel, Limassol, Cyprus. It is organized by the University of Cyprus, which co-sponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA). ETS traditionally enjoys a strong balance among academic and industrial participants. In addition to regular Scientific Papers, Special Sessions, Panels, and Embedded Tutorials, ETS features Vendor Sessions and Table-Top Demos, a special track on Emerging Test Strategies (ETS²) where new issues are presented by the industry and are discussed in an informal atmosphere, as well as the new initiative of Industry Wish List where industry presents elevator talks on open issues demanding urgent solutions. ETS is the major event of the European Test Week, which includes TSS (Test Spring School) and fringe workshops.

You are invited to participate and submit your contributions to ETS'17. The areas of interest include (but are not limited to) the following topics:

- Analog Test
- ATE Hardware and Software
- Automatic Test Generation
- Board Test and Diagnosis
- Boundary Scan Test
- Built-In Self-Test (BIST)
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability and Functional Safety
- Design for Test (DfT)
- Design for Manufacturing (DfM)
- Diagnosis and Silicon Debug
- Economics of Test
- Emerging Technologies
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- GPU Test
- High-Speed I/O Test
- Low-Power IC Test
- Memory Test and Repair
- MEMS Test
- Microprocessor Test
- Mixed-Signal Test
- Multi-/Many-core Processor Test
- Nanotechnology Test
- On-line Test
- Power Issues in Test
- Reconfigurable System Test
- Reliability
- RF Test
- Security and Trust Issues in Test
- Self-Repair
- Sensor Test
- Signal Integrity Test
- SiP, Stacked, 3D IC Test
- SoC Test
- Soft Errors
- Standards in Test
- Statistical Learning in Test
- Test Compression
- Test Quality
- Test Synthesis
- Thermal Issues in Test
- Validation and Verification
- Variability Issues in Test
- Yield Analysis and Enhancement

Publication – ETS'17 will produce electronic formal proceedings with ISBN number to be indexed in the IEEE Xplore Digital Library and other bibliographical search engines.

Submissions – ETS'17 seeks:

- **Scientific Papers** for the Formal Proceedings, presenting novel, unpublished, and complete research work. Prospective authors should be aware that ETS'17 fully complies with the IEEE publication policies regarding multiple submissions, plagiarism, etc.

Key Dates for scientific papers:	○ Submission of title, abstract, authors:	December 5
	○ Full submission:	December 13, 2016
	○ Notification of acceptance:	February 10, 2017
	○ Camera-ready manuscript:	March 17, 2017

ETS'17 also seeks proposals for:

- **Special Sessions, Panels, and Embedded Tutorials.**
- Special Session contributions to the special track on **Emerging Test Strategies (ETS²)**.
- **Vendor and Table-Top Demos presentations** focusing on new features of test related products.
- **Fringe Workshops**, to be held during May 25-26, 2017.
- **Fringe Meetings**, to be held during the European Test Week.

Key dates regarding the submission of proposals in the above categories can be found on the website.

Further Information:

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